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Soggetti	Artificial intelligence
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	Computers
	Database management
	Application software
	Artificial Intelligence
	Algorithm Analysis and Problem Complexity Probability and Statistics in Computer Science
	Computation by Abstract Devices
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Nota di contenuto	Effectiveness of graphical models including modeling. Reasoning, model selection Logic-probability relations Causality. Applying graphical models in real world settings Scalability Incremental learningParallelization.

1.

This volume constitutes the refereed proceedings of the Second International Workshop on Advanced Methodologies for Bayesian Networks, AMBN 2015, held in Yokohama, Japan, in November 2015. The 18 revised full papers and 6 invited abstracts presented were carefully reviewed and selected from numerous submissions. In the International Workshop on Advanced Methodologies for Bayesian Networks (AMBN), the researchers explore methodologies for enhancing the effectiveness of graphical models including modeling, reasoning, model selection, logic-probability relations, and causality. The exploration of methodologies is complemented discussions of practical considerations for applying graphical models in real world settings, covering concerns like scalability, incremental learning, parallelization, and so on.